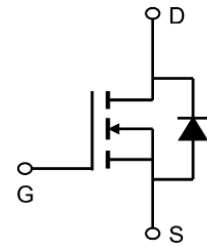


## 30V N-Channel Enhancement Mode MOSFET

### Description

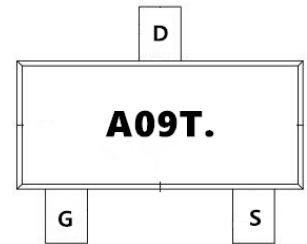
The AP3400BI uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.



### General Features

$V_{DS} = 30V$   $I_D = 5.8A$

$R_{DS(ON)} < 28m\Omega @ V_{GS}=10V$  (Type: 26m $\Omega$ )



### Application

- Battery protection
- Load switch
- Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP3400BI	SOT23L	A09T.	3000

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V
$I_D @ T_A=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 4.5V^1$	5.8	A
$I_D @ T_A=70^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 4.5V^1$	3.1	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	16	A
$P_D @ T_A=25^\circ\text{C}$	Total Power Dissipation <sup>3</sup>	1	W
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-ambient <sup>1</sup>	125	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	80	$^\circ\text{C/W}$

## 30V N-Channel Enhancement Mode MOSFET

### Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)

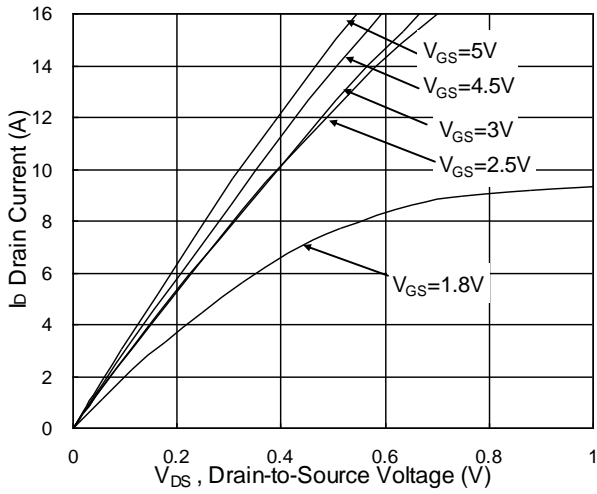
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	32	---	V
$\Delta BVDSS/\Delta T_J$	BVDSS Temperature Coefficient	Reference to $25^{\circ}\text{C}$ , $I_D=1\text{mA}$	---	0.029	---	V/ $^{\circ}\text{C}$
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10V, I_D=4A$		26	28	m $\Omega$
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=4.5V, I_D=3A$	---	29	32	m $\Omega$
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=2.5V, I_D=2A$	---	38	47	m $\Omega$
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	0.5	0.95	1.2	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	-2.82	---	mV/ $^{\circ}\text{C}$
IDSS	Drain-Source Leakage Current	$V_{DS}=24V, V_{GS}=0V, T_J=25^{\circ}\text{C}$	---	---	1	uA
		$V_{DS}=24V, V_{GS}=0V, T_J=55^{\circ}\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	---	---	$\pm 100$	nA
gfs	Forward Transconductance	$V_{DS}=5V, I_D=3A$	---	19	---	S
Rg	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$	---	1.5	3	$\Omega$
Qg	Total Gate Charge (4.5V)	$V_{DS}=15V, V_{GS}=4.5V, I_D=3A$	---	8.34	11.7	nC
Qgs	Gate-Source Charge		---	1.26	1.8	
Qgd	Gate-Drain Charge		---	1.88	2.6	
Td(on)	Turn-On Delay Time	$V_{DD}=15V, V_{GS}=4.5V, R_G=3.3\Omega, I_D=3A$	---	3.2	6.4	ns
Tr	Rise Time		---	41.8	75	
Td(off)	Turn-Off Delay Time		---	21.2	42	
Tf	Fall Time		---	6.4	12.8	
Ciss	Input Capacitance	$V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$	---	662	927	pF
Coss	Output Capacitance		---	51.3	72	
Crss	Reverse Transfer Capacitance		---	43.6	61	
IS	Continuous Source Current <sup>1,4</sup>	$V_G=V_D=0V$ , Force Current	---	---	3.9	A
ISM	Pulsed Source Current <sup>2,4</sup>	$V_{GS}=0V, I_S=1A, T_J=25^{\circ}\text{C}$	---	---	16	A
VSD	Diode Forward Voltage <sup>2</sup>		---	---	1.2	V
trr	Reverse Recovery Time	$I_F=3A, dI/dt=100A/\mu s, T_J=25^{\circ}\text{C}$	---	6.8	---	nS
Qrr	Reverse Recovery Charge		---	2.3	---	nC

#### Note :

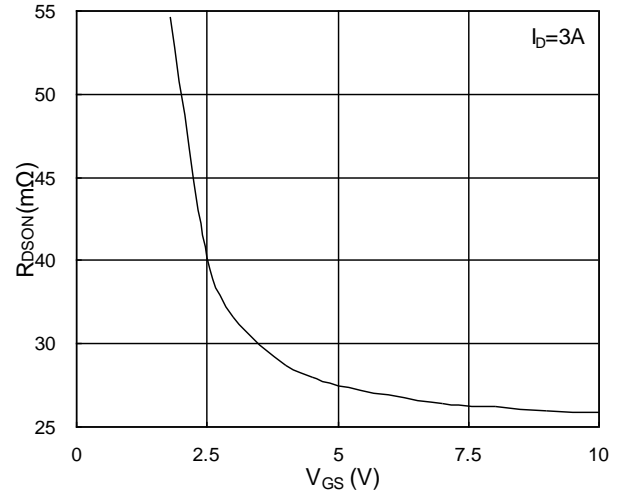
- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
- 4、The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

**30V N-Channel Enhancement Mode MOSFET**

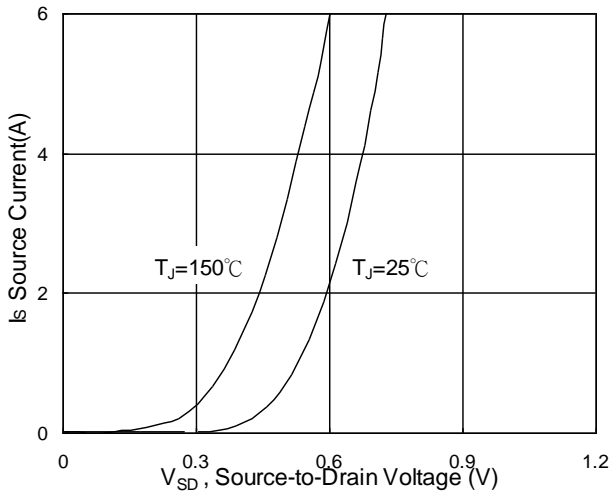
**Typical Characteristics**



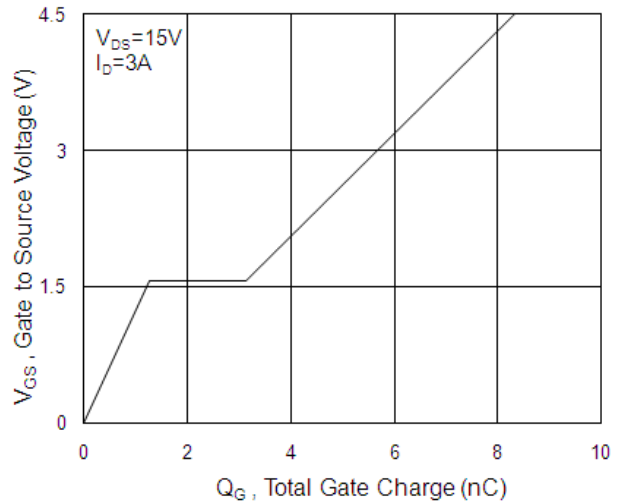
**Fig.1 Typical Output Characteristics**



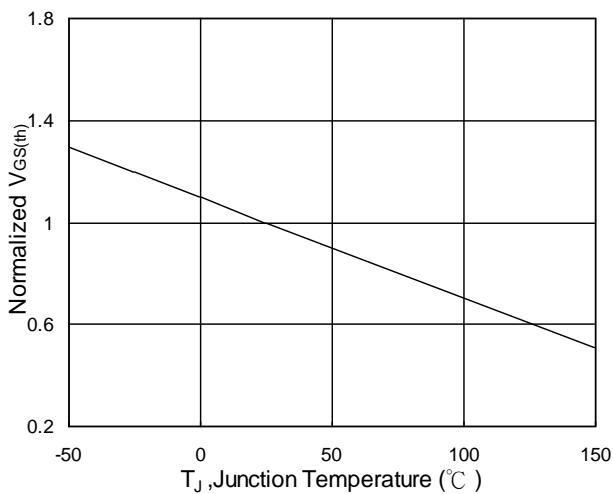
**Fig.2 On-Resistance vs G-S Voltage**



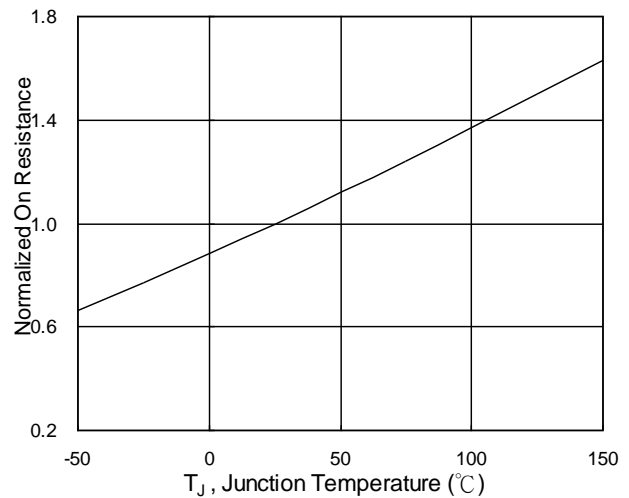
**Fig.3 Source Drain Forward Characteristics**



**Fig.4 Gate-Charge Characteristics**



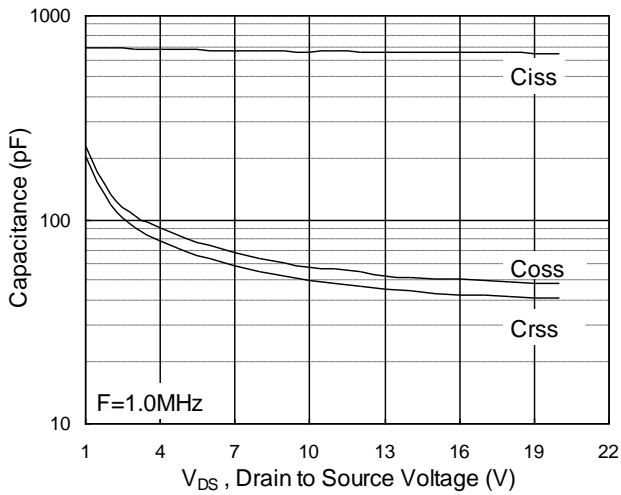
**Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$**



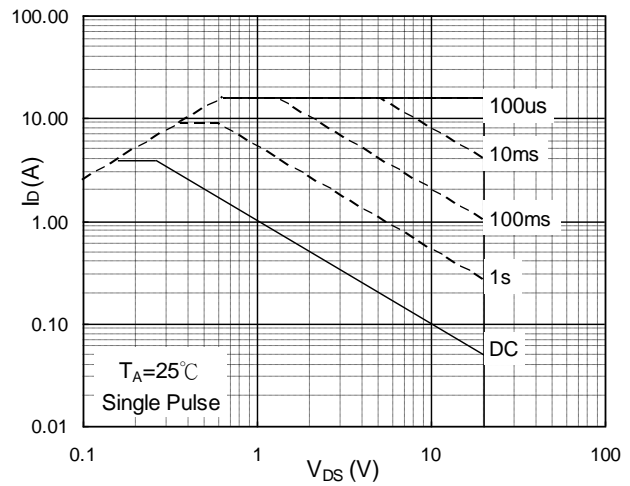
**Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$**



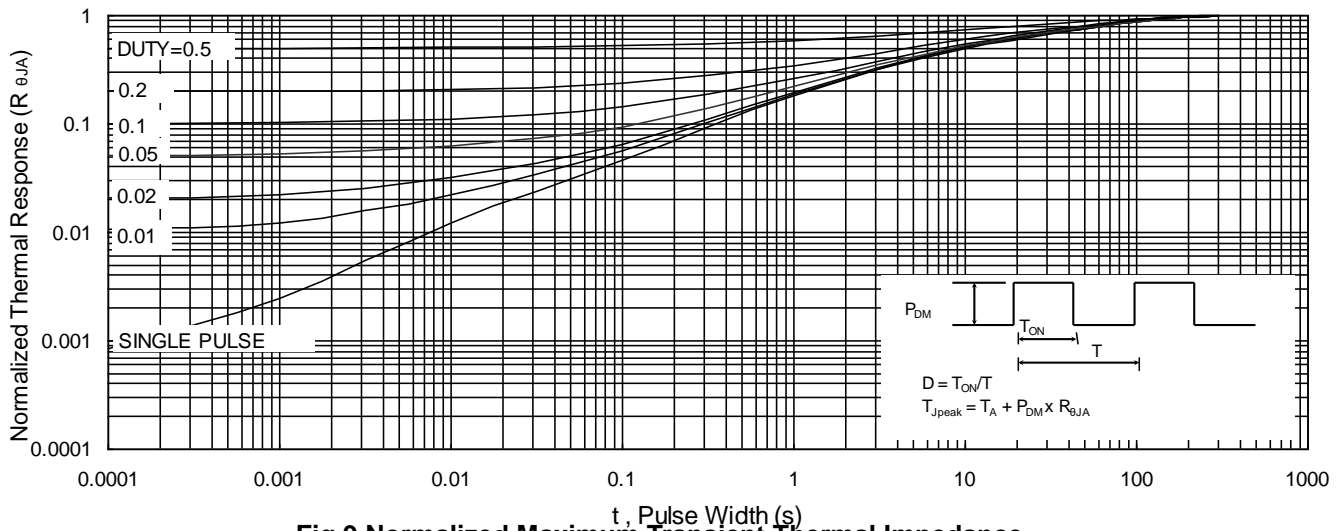
**30V N-Channel Enhancement Mode MOSFET**



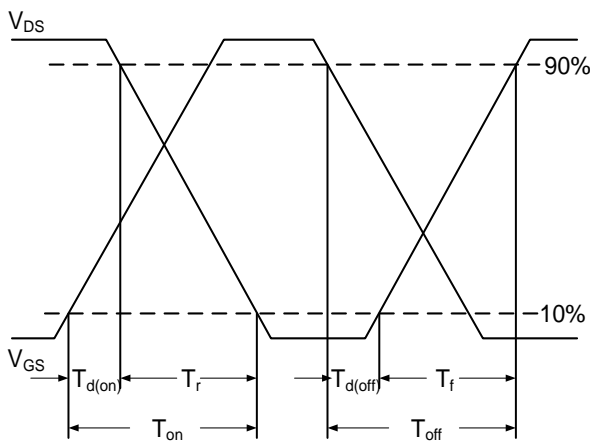
**Fig.7 Capacitance**



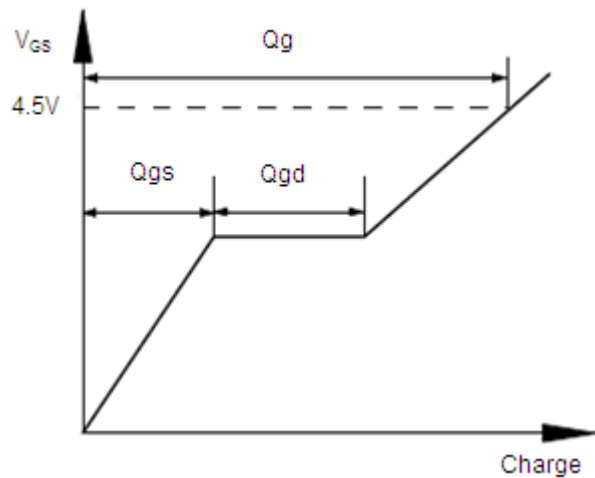
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

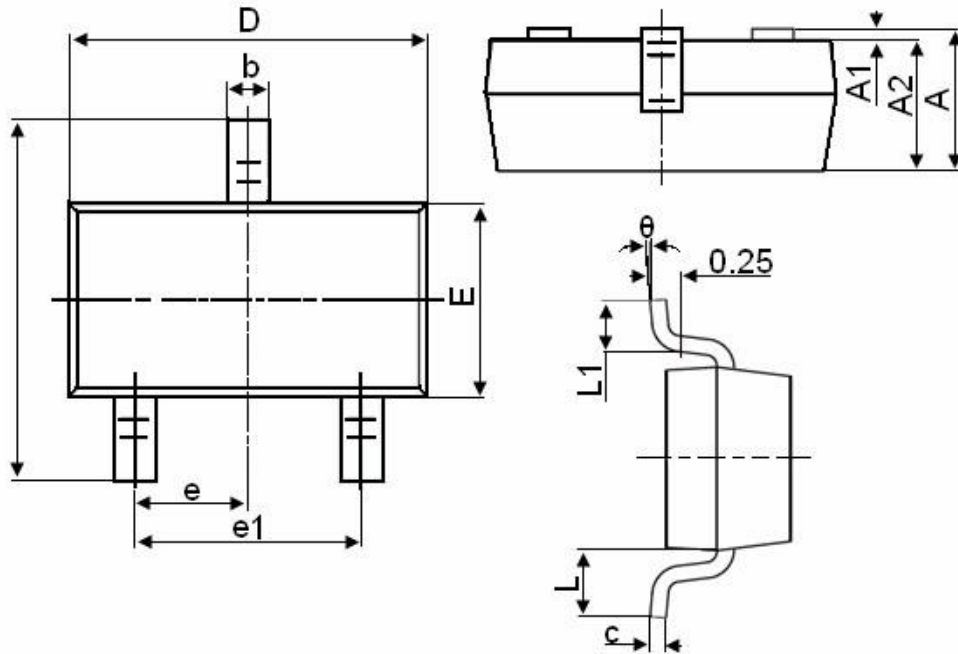


**Fig.10 Switching Time Waveform**



**Fig.11 Gate Charge Waveform**

Package Mechanical Data-SOT23-XC-Single



Symbol	Dimensions in Millimeters	
	MIN.	MAX.
A	0.900	1.150
A1	0.000	0.100
A2	0.900	1.050
b	0.300	0.500
c	0.080	0.150
D	2.800	3.000
E	1.200	1.400
E1	2.250	2.550
e	0.950TYP	
e1	1.800	2.000
L	0.550REF	
L1	0.300	0.500
$\theta$	0°	8°

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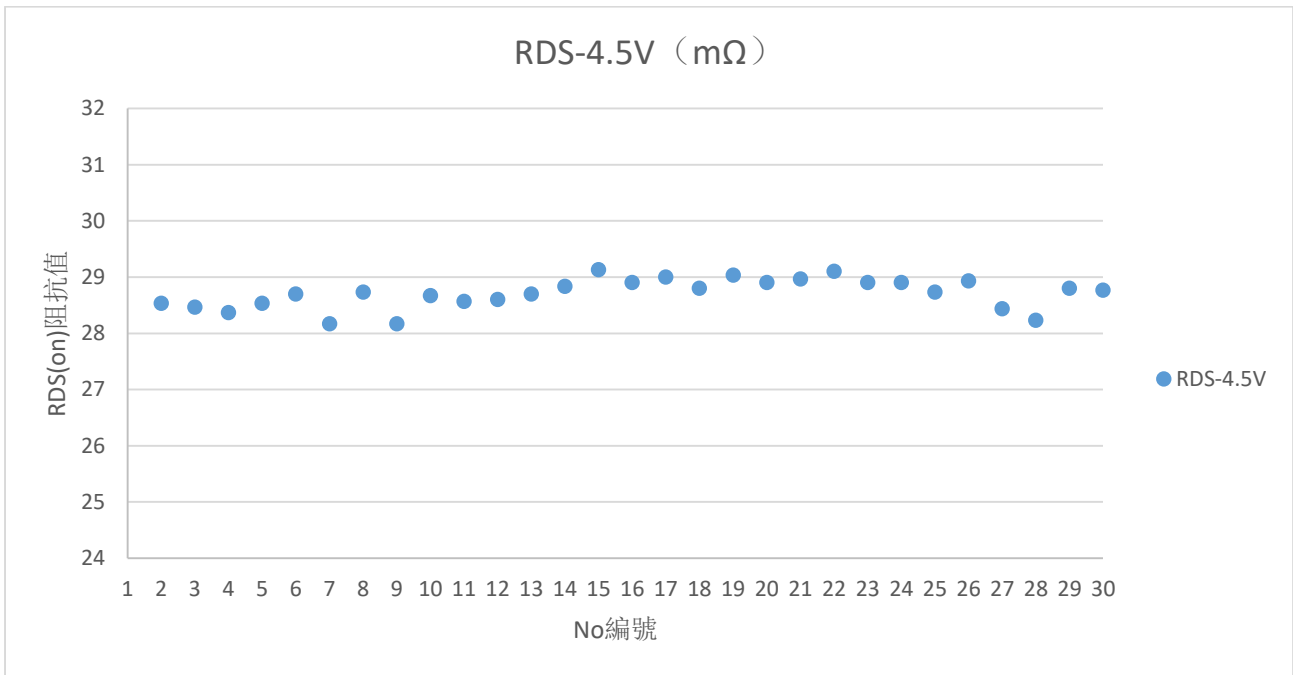
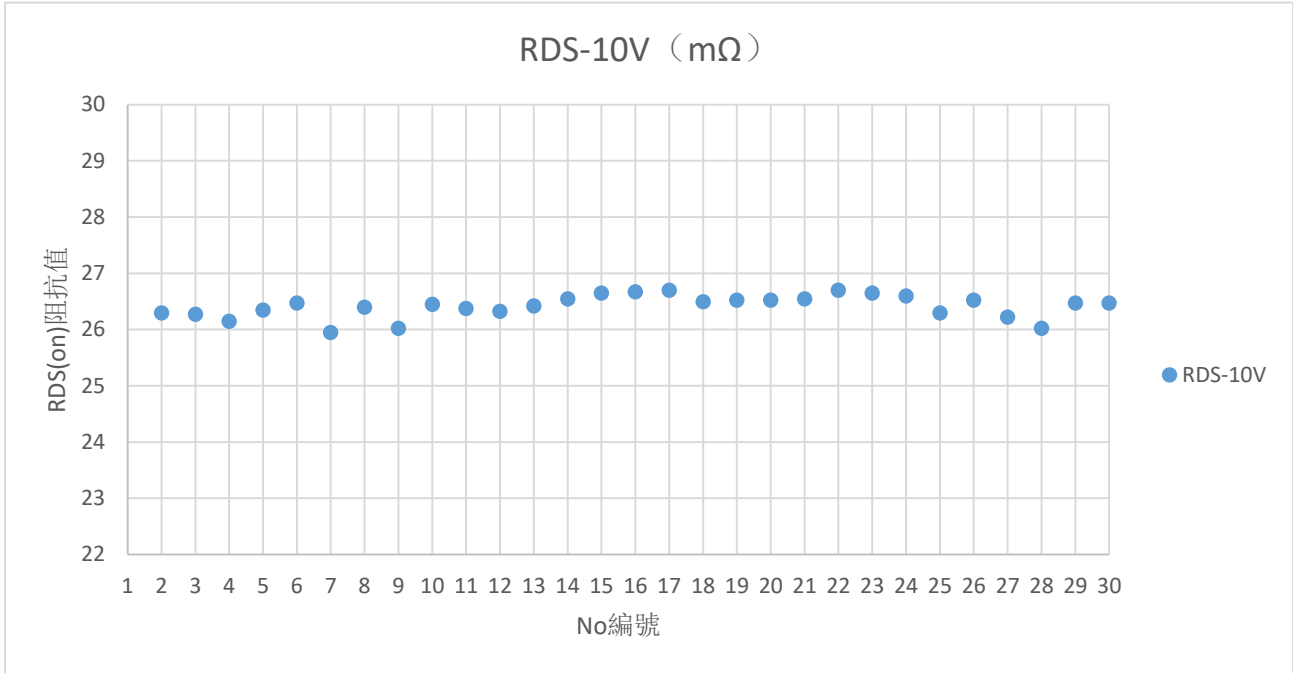
**30V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
Rve1.0	2020/5/1	Initial release

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**Test Report For 30PCS (30pcs 典型測試報告)**







## 30V N-Channel Enhancement Mode MOSFET

